Applicant(s)/Patent Under Application/Control No. Reexamination 09/903,211 HIRATSUKA ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2826 A. Sefer **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-6,020,867 02-2000 Shimada et al. 345/87 Α US-6,492,587 12-2002 174/350 Yoshinaga, Takashi В 03-2002 US-6,359,390 Nagai, Takayoshi 315/169.1 С US-D Ε US-US-F US-G US-Н US-1 US-US-Κ US-US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification MM-YYYY Country Code-Number-Kind Code Ν 0 Р Q

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